

1) RAM Capacity: N -address lines and M -bit wide data
 Storage capacity = $M 2^N$

Example: $N=8$, $M=8$

$$M 2^N = 2048 \text{ bits} = 2 \text{ Kbits of memory}$$

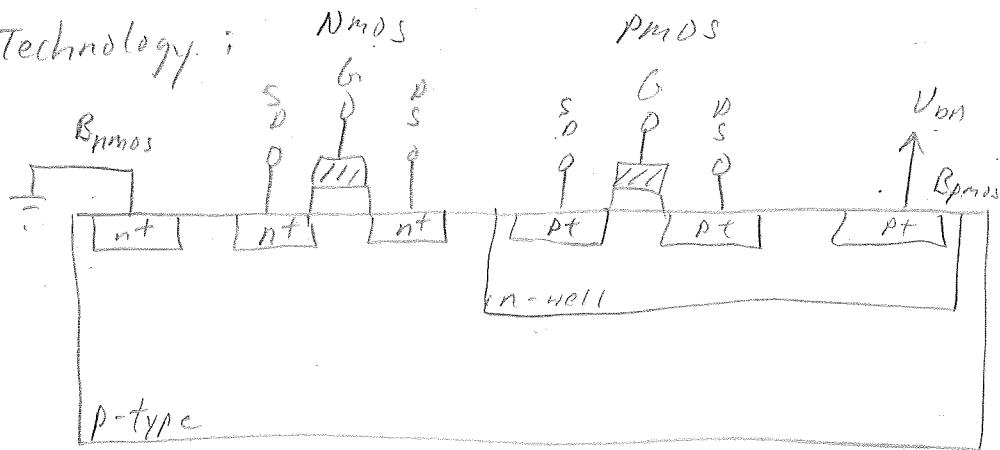
2) Decoder Architecture Comparison

# Inputs	<u>NAND Logic Circuit</u> # Ts	<u>Transistor NAND-Equivalent</u> # Ts
2	$4 + 4(4) + 4(2) = 28$	$2(4) + 4 + 4(2) + 4(2) = 28$
3	$6 + 8(6) + 8(2) = 70$	$3(4) + 8 + 8(3) + 8(2) = 60$
4	$8 + 16(8) + 16(2) = 168$	$4(4) + 16 + 16(4) + 16(2) = 128$
5	$10 + 32(10) + 32(2) = 394$	$5(4) + 32 + 32(5) + 32(2) = 276$

As N increases, the transistor NAND-Equivalent Decoder requires a lot fewer Ts than the NAND Logic Circuit Decoder.

Bidirectional Operation of the MOSFET

CMOS Technology:



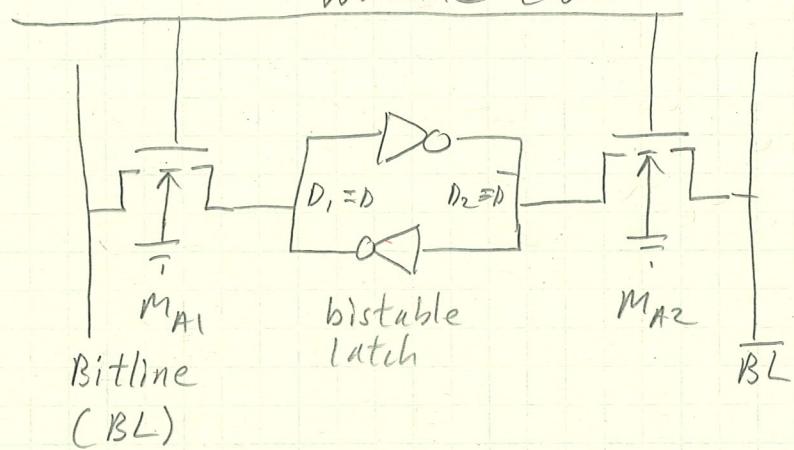
With the Body contacts properly connected; $B_p \rightarrow OV$, $B_n \rightarrow V_{DD}$ current can flow either way between non-gate NMOS & PMOS terminals for $OV \leq V \leq V_{DD}$.

Relative voltages determine which is S and D.

Note: Body effect increases V_{TN} and $|V_{TP}|$ if S is not connected to same voltage as B for that transistor

→ This is used in Read and Write operations with memory cells

standard SRAM Memory cell \rightarrow 6-T cell
 Wordline (WL)



$M_{A1} \wedge M_{A2} \rightarrow$ NMOS T's \rightarrow used as low R switches

D = stored data value

stored 0 ($D=0$) : $D_1=0, D_2=1$

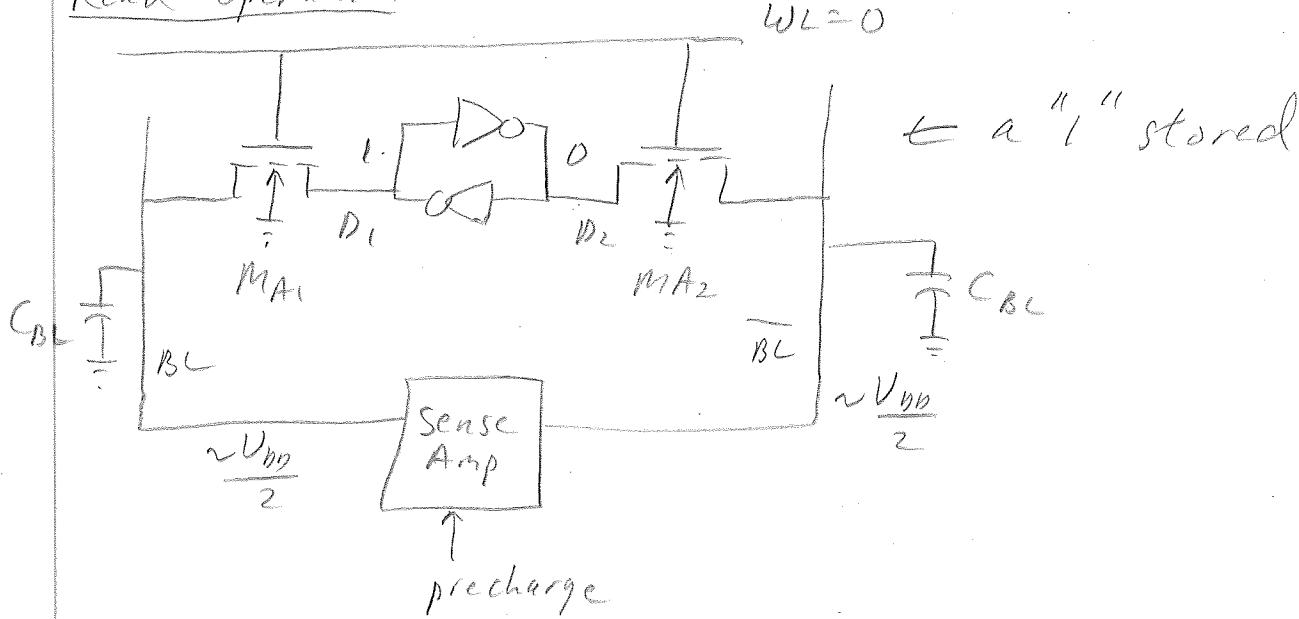
stored 1 ($D=1$) : $D_1=1, D_2=0$

$WL=0 \rightarrow$ bistable latch unaffected

$WL=1 \rightarrow M_{A1} \wedge M_{A2}$ on \rightarrow connects bistable latch to BL and \bar{BL} to read the value stored in the bistable latch or to write a value (1 or 0) to it.

M_{A1} and M_{A2} take advantage of the bidirectional operation of MOSFETs

Read Operation



With WL off ($WL=0$), $BL + \bar{BL}$ charged up to approximately $\frac{V_{DD}}{2}$.

C_{BL} → parasitic capacitance on the $BL + \bar{BL}$ line

→ when WL goes high : $D_1 = V_{DD}$ pulls BL higher, and $D_2 = 0V$ pulls \bar{BL} lower.

→ The sense Amp detects this and amplifies the effect → pushing $BL \rightarrow V_{DD}$ and $\bar{BL} \rightarrow GND$

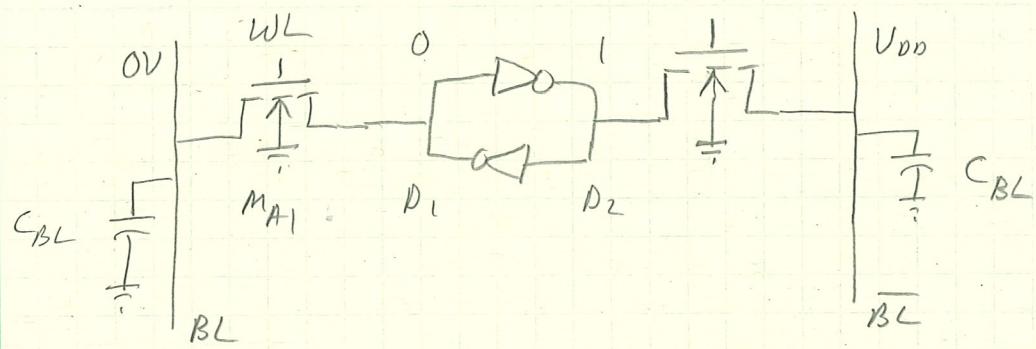
→ The opposite happens when a "0" is stored

→ The result is detected as a stored "1" or "0" by the Sense Amp

→ Since neither side of the bistable latch experiences its voltage crossing V_{trip} , the stored state does not change

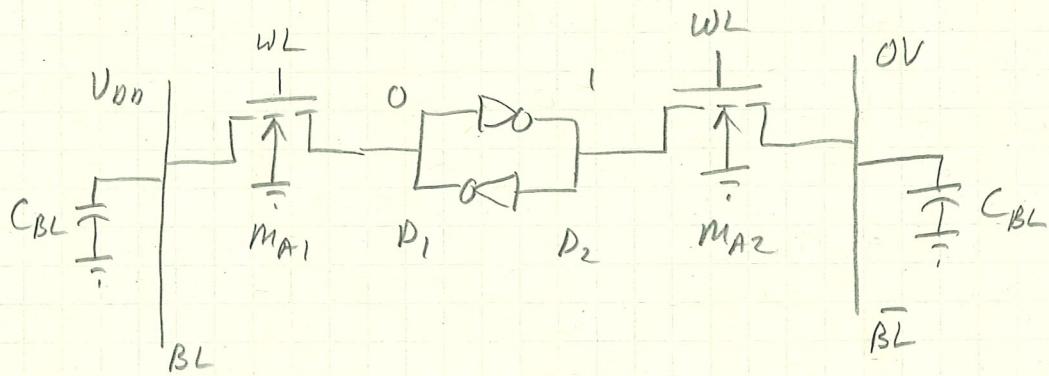
Write Operation

Writing a "0" to a stored "0"



When $WL \rightarrow V_{DD}$, M_{A1} and M_{A2} turn on. But since $BL = D_1 = OV$ and $\bar{BL} = D_2 = V_{DD}$, no change to the Bistable Latch occurs

Writing a "1" to a stored "0"

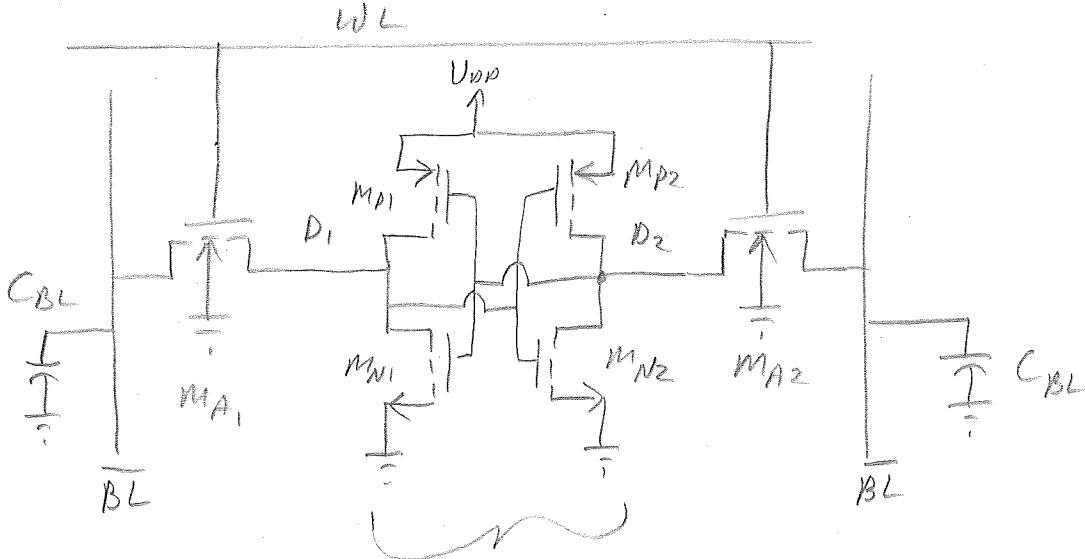


When $WL \rightarrow V_{DD}$ and M_{A1} and M_{A2} turn on, D_1 is connected to BL at V_{DD} and D_2 is connected to \bar{BL} at OV .

This is enough to cause the voltages at D_1 and D_2 to cross the inverter trip voltages. Then positive feedback in the bistable latch moves D_1 to V_{DD} and D_2 to OV .

The opposite happens when writing a "0" to the bistable latch with a previously stored "1"

Transistor Schematic of the 6-T Cell



Bistable Latch

Observe cross-coupled connections

In steady state: M_{N1} and M_{N2} on and M_{P1} and M_{P2} off
or M_{N1} and M_{P2} off and M_{P1} and M_{N2} on